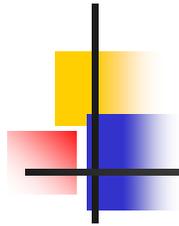


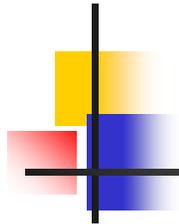
3.155J/6.152J Lecture 22: Take Home Exam Discussion

Prof. Martin A. Schmidt
Massachusetts Institute of Technology
12/5/2005



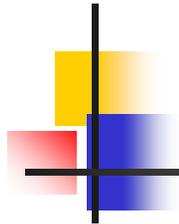
Outline

- Review of Schedule
- The Knowles Microphone



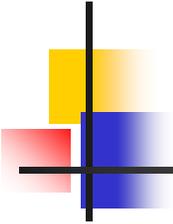
Schedule

- Week of 12/5
 - Monday – Take Home Discussion
 - Wednesday – Prof. Joel Voldman – Biological and Medical Applications of Micro/Nano Fab
 - Fluids Lab Due
 - Course Evaluation
- Week of 12/12
 - Monday – Prof. Leslie Kolodziejski – Photonic Devices and Compound Semiconductors
 - Wednesday – Analog Devices Tour
 - Take Home Due



Take Home Design Challenge

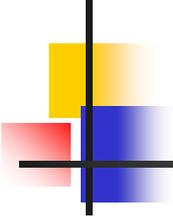
- Design a process for fabrication of a microphone integrated with a depletion mode nMOSFET
- Utilize the Knowles microphone as our model device
 - U.S. Patent 6,847,090
 - 'Silicon Capacitive Microphone' - Loeppert



Microphone Cross-Section

Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.



Microphone Cross-Section

Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

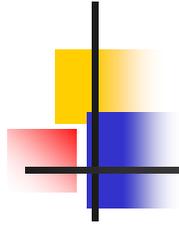
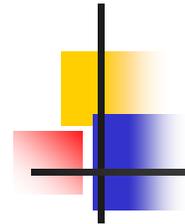


Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

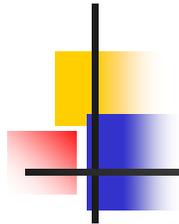


Microphone Cross-Section

Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

How are the electrical connections made?

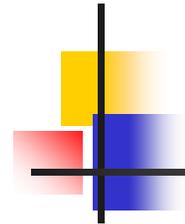


Starting Materials

Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

- Membrane (1)
 - Stress-compensated boron-doped etch stop
 - Lightly doped silicon with buried etch stop
 - Boron-doped silicon or oxide
- Backplane (2)
 - Boron-doped silicon

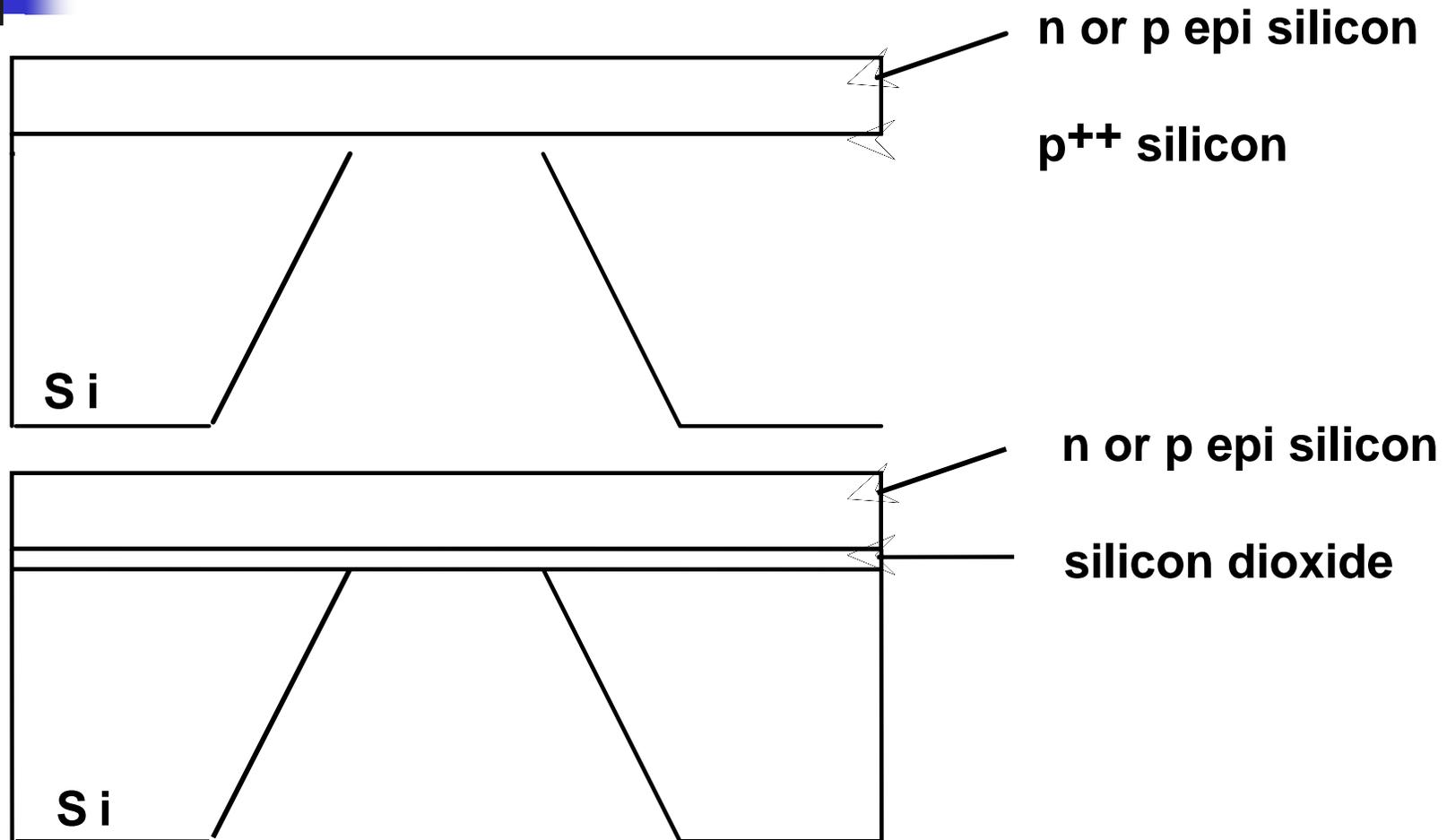


Boron Etch Stop

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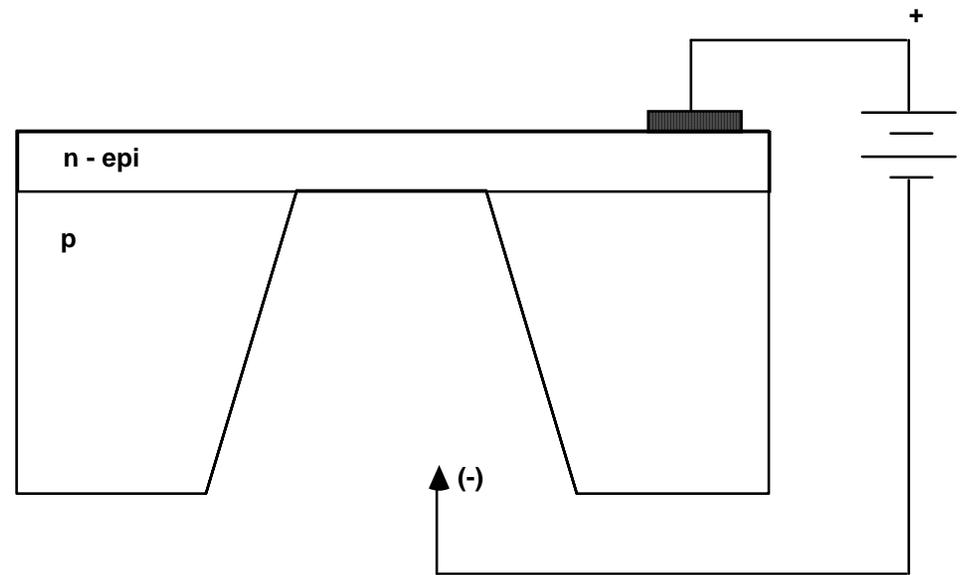
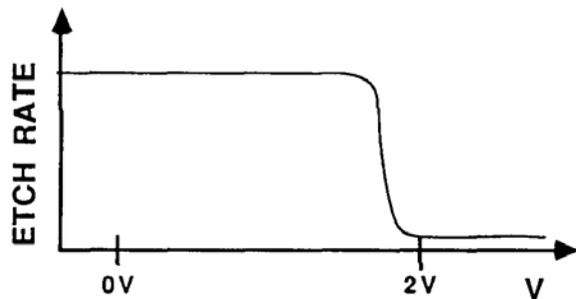
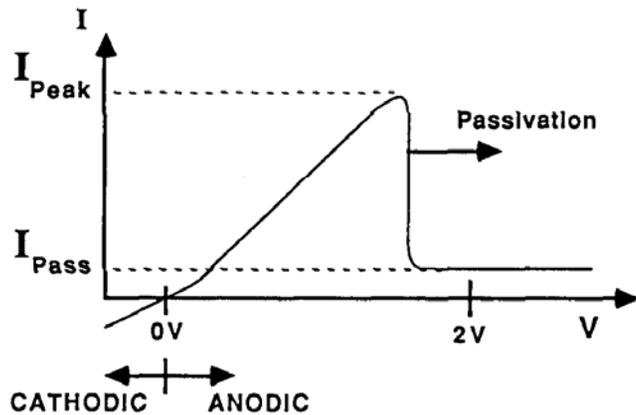
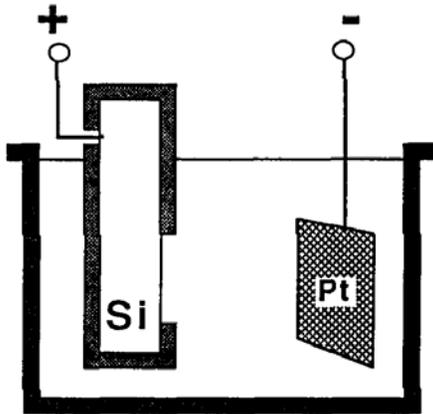
Figure found in H. Seidel, L. Csepregi, A.Hueberger, and H. Baungärtel. *The Journal of the Electrochemical Society* 137 (1990): 3612-3626.

Buried Etch Stops



Masking material: silicon dioxide or silicon nitride

Electrochemical Etch-stop



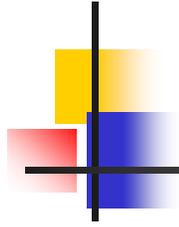


Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

- Pattern insulating layer (oxide)
- Etch trenches

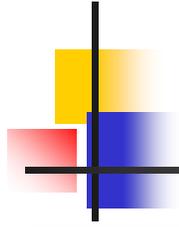


Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

- Silicon Fusion Bonding
 - Clean (RCA) both wafers
 - Contact
 - Reduced atmosphere ambient
 - Anneal 1000C, 1hour

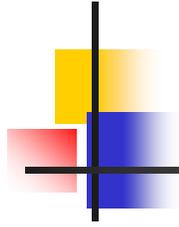


Figure removed for copyright reasons.

Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

- Substrate Etch
 - Masking material
 - Boron etch stop ($N > 10^{20} \text{ cm}^{-3}$)
 - Alternatives
 - SOI, Electrochemical

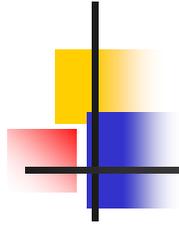
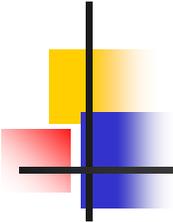


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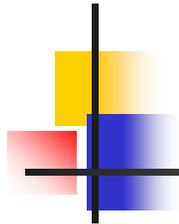
Loeppert "Silicon Capacitive Microphone." U.S. Patent 6,847,090.

■ Trench Etch



Integration with nMOS

- Isolation
 - Can utilize oxide isolation
- Move cavity etch to end of process
 - Requires a means to protect the wafer frontside
- Interconnect
 - Need to connect FET to capacitor plate, and provide metal covered connections to other plates of capacitor
- Process 'ease'
 - Some steps hard (e.g. handling a wafer with holes)



Next steps

- Complete Take Home Problem Statement will be handed out / posted on Wednesday
- Solution due on Wednesday